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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	32-Bit Single-Core
Speed	66MHz
Connectivity	CANbus, Ethernet, I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	81
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x12b; D/A 4x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/at32uc3c1512c-aur

The Full-Speed USB 2.0 Device interface supports several USB Classes at the same time thanks to the rich End-Point configuration. The On-The-GO (OTG) Host interface allows device like a USB Flash disk or a USB printer to be directly connected to the processor.

The media-independent interface (MII) and reduced MII (RMII) 10/100 Ethernet MAC module provides on-chip solutions for network-connected devices.

The Peripheral Event Controller (PEVC) allows to redirect events from one peripheral or from input pins to another peripheral. It can then trigger, in a deterministic time, an action inside a peripheral without the need of CPU. For instance a PWM waveform can directly trigger an ADC capture, hence avoiding delays due to software interrupt processing.

The AT32UC3C features analog functions like ADC, DAC, Analog comparators. The ADC interface is built around a 12-bit pipelined ADC core and is able to control two independent 8-channel or one 16-channel. The ADC block is able to measure two different voltages sampled at the same time. The analog comparators can be paired to detect when the sensing voltage is within or outside the defined reference window.

Atmel offers the QTouch library for embedding capacitive touch buttons, sliders, and wheels functionality into AVR microcontrollers. The patented charge-transfer signal acquisition offers robust sensing and included fully debounced reporting of touch keys and includes Adjacent Key Suppression® (AKS®) technology for unambiguous detection of key events. The easy-to-use QTouch Suite toolchain allows you to explore, develop, and debug your own touch applications.

AT32UC3C integrates a class 2+ Nexus 2.0 On-Chip Debug (OCD) System, with non-intrusive real-time trace, full-speed read/write memory access in addition to basic runtime control. The Nanotrace interface enables trace feature for aWire- or JTAG-based debuggers. The single-pin aWire interface allows all features available through the JTAG interface to be accessed through the RESET pin, allowing the JTAG pins to be used for GPIO or peripherals.

2. Overview

2.1 Block diagram

Figure 2-1. Block diagram

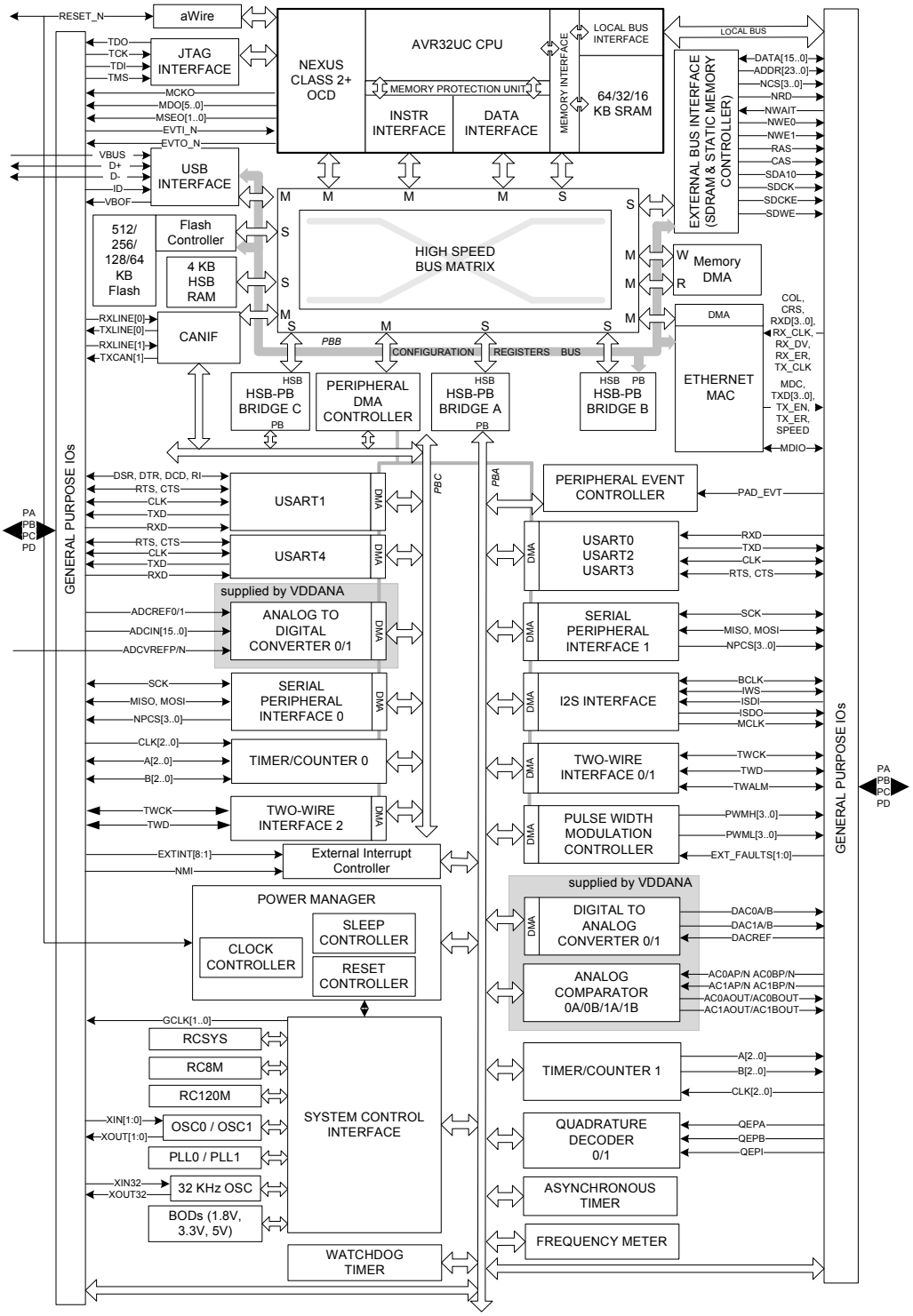


Table 3-1. GPIO Controller Function Multiplexing

TQFP / QFN 64	TQFP 100	LQFP 144	PIN	GPIO	Supply	Pin Type (1)	GPIO function					
							A	B	C	D	E	F
		14	PB11	43	VDDIO1	x1/x2	USART1 - DSR	SPI0 - MISO	PWM - PWMH[1]			
		15	PB12	44	VDDIO1	x1/x2	USART1 - DCD	SPI0 - SCK	PWM - PWML[2]			
		16	PB13	45	VDDIO1	x1/x2	USART1 - RI	SPI0 - NPCS[0]	PWM - PWMH[2]		MACB - RX_ER	
		17	PB14	46	VDDIO1	x1/x2	USART1 - RTS	SPI0 - NPCS[1]	PWM - PWML[3]		MACB - MDC	
		18	PB15	47	VDDIO1	x1/x2	USART1 - CTS	USART1 - CLK	PWM - PWMH[3]		MACB - MDIO	
		19	PB16	48	VDDIO1	x1/x2	USART1 - RXD	SPI0 - NPCS[2]	PWM - EXT_ FAULTS[0]		CANIF - RXLINE[0]	
		20	PB17	49	VDDIO1	x1/x2	USART1 - TXD	SPI0 - NPCS[3]	PWM - EXT_ FAULTS[1]		CANIF - TXLINE[0]	
		57	PB18	50	VDDIO2	x1/x2	TC0 - CLK2		EIC - EXTINT[4]			
	42	58	PB19	51	VDDIO2	x1/x2	TC0 - A0	SPI1 - MOSI	IISC - ISDO		MACB - CRS	
	43	59	PB20	52	VDDIO2	x1/x2	TC0 - B0	SPI1 - MISO	IISC - ISDI	ACIFA1 - ACAOUT	MACB - COL	
	44	60	PB21	53	VDDIO2	x2/x4	TC0 - CLK1	SPI1 - SCK	IISC - IMCK	ACIFA1 - ACBOUT	MACB - RXD[2]	
	45	61	PB22	54	VDDIO2	x1/x2	TC0 - A1	SPI1 - NPCS[3]	IISC - ISCK	SCIF - GCLK[0]	MACB - RXD[3]	
	46	62	PB23	55	VDDIO2	x1/x2	TC0 - B1	SPI1 - NPCS[2]	IISC - IWS	SCIF - GCLK[1]	MACB - RX_CLK	
		63	PB24	56	VDDIO2	x1/x2	TC0 - CLK0	SPI1 - NPCS[1]				
		64	PB25	57	VDDIO2	x1/x2	TC0 - A2	SPI1 - NPCS[0]	PEVC - PAD_EVT [8]			
		65	PB26	58	VDDIO2	x2/x4	TC0 - B2	SPI1 - SCK	PEVC - PAD_EVT [9]		MACB - TX_EN	
		66	PB27	59	VDDIO2	x1/x2	QDEC0 - QEPA	SPI1 - MISO	PEVC - PAD_EVT [10]	TC1 - CLK0	MACB - TXD[0]	
		67	PB28	60	VDDIO2	x1/x2	QDEC0 - QEPB	SPI1 - MOSI	PEVC - PAD_EVT [11]	TC1 - B0	MACB - TXD[1]	
		68	PB29	61	VDDIO2	x1/x2	QDEC0 - QEPI	SPI0 - NPCS[0]	PEVC - PAD_EVT [12]	TC1 - A0		
31	47	69	PB30	62	VDDIO2	x1						
32	48	70	PB31	63	VDDIO2	x1						
	49	71	PC00	64	VDDIO2	x1/x2	USBC - ID	SPI0 - NPCS[1]	USART2 - CTS	TC1 - B2	CANIF - TXLINE[1]	
	50	72	PC01	65	VDDIO2	x1/x2	USBC - VBOF	SPI0 - NPCS[2]	USART2 - RTS	TC1 - A2	CANIF - RXLINE[1]	

Table 3-2. Peripheral Functions

Function	Description
aWire DATAOUT	aWire output in two-pin mode
JTAG port connections	JTAG debug port
Oscillators	OSC0, OSC32

3.2.3 Oscillator Pinout

The oscillators are not mapped to the normal GPIO functions and their muxings are controlled by registers in the System Control Interface (SCIF). Please refer to the SCIF chapter for more information about this.

Table 3-3. Oscillator pinout

QFN64/ TQFP64 pin	TQFP100 pin	LQFP144 pin	Pad	Oscillator pin
31	47	69	PB30	xin0
	99	143	PB02	xin1
62	96	140	PB00	xin32
32	48	70	PB31	xout0
	100	144	PB03	xout1
63	97	141	PB01	xout32

3.2.4 JTAG port connections

If the JTAG is enabled, the JTAG will take control over a number of pins, irrespectively of the I/O Controller configuration.

Table 3-4. JTAG pinout

QFN64/ TQFP64 pin	TQFP100 pin	LQFP144 pin	Pin name	JTAG pin
2	2	2	PA01	TDI
3	3	3	PA02	TDO
4	4	4	PA03	TMS
1	1	1	PA00	TCK

3.2.5 Nexus OCD AUX port connections

If the OCD trace system is enabled, the trace system will take control over a number of pins, irrespectively of the GPIO configuration. Three different OCD trace pin mappings are possible,

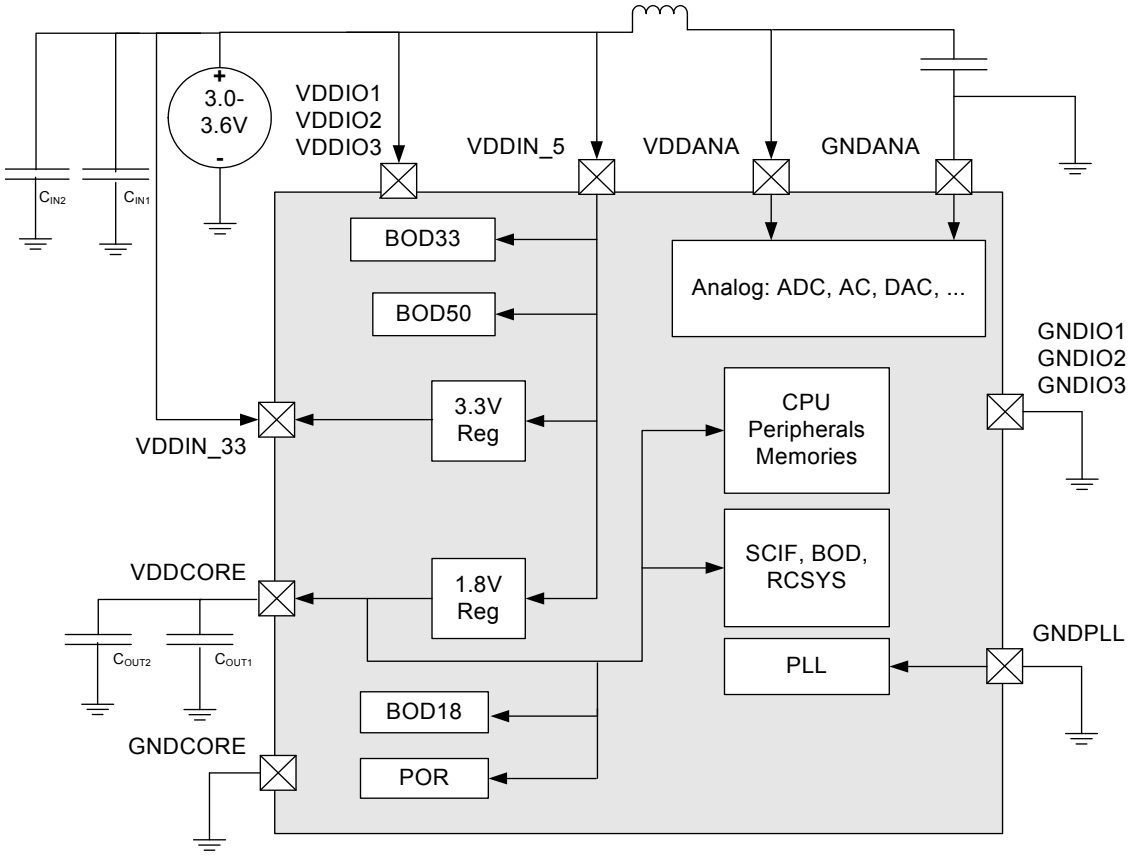
Table 3-7. Signal Description List

Signal Name	Function	Type	Active Level	Comments
VDDIN_5	1.8V Voltage Regulator Input	Power Input		Power Supply: 4.5V to 5.5V or 3.0V to 3.6 V
VDDIN_33	USB I/O power supply	Power Output/ Input		Capacitor Connection for the 3.3V voltage regulator or power supply: 3.0V to 3.6 V
VDDCORE	1.8V Voltage Regulator Output	Power output		Capacitor Connection for the 1.8V voltage regulator
GNDIO1 GNDIO2 GNDIO3	I/O Ground	Ground		
GNDANA	Analog Ground	Ground		
GNDCORE	Ground of the core	Ground		
GNDPLL	Ground of the PLLs	Ground		
Analog Comparator Interface - ACIFA0/1				
AC0AN1/AC0AN0	Negative inputs for comparator AC0A	Analog		
AC0AP1/AC0AP0	Positive inputs for comparator AC0A	Analog		
AC0BN1/AC0BN0	Negative inputs for comparator AC0B	Analog		
AC0BP1/AC0BP0	Positive inputs for comparator AC0B	Analog		
AC1AN1/AC1AN0	Negative inputs for comparator AC1A	Analog		
AC1AP1/AC1AP0	Positive inputs for comparator AC1A	Analog		
AC1BN1/AC1BN0	Negative inputs for comparator AC1B	Analog		
AC1BP1/AC1BP0	Positive inputs for comparator AC1B	Analog		
ACAOUT/ACBOUT	analog comparator outputs	output		
ADC Interface - ADCIFA				
ADCIN[15:0]	ADC input pins	Analog		
ADCREF0	Analog positive reference 0 voltage input	Analog		
ADCREF1	Analog positive reference 1 voltage input	Analog		
ADCVREFP	Analog positive reference connected to external capacitor	Analog		

than the oldest instruction. An instruction B is younger than an instruction A if it was sent down the pipeline later than A.

The addresses and priority of simultaneous events are shown in Table 4-4 on page 38. Some of the exceptions are unused in AVR32UC since it has no MMU, coprocessor interface, or floating-point unit.

Figure 6-2. 3 Single Power Supply Mode



6.1.4 Power-up Sequence

6.1.4.1 Maximum Rise Rate

To avoid risk of latch-up, the rise rate of the power supplies must not exceed the values described in Table 7-2 on page 51 .

Recommended order for power supplies is also described in this table.

6.1.4.2 Minimum Rise Rate

The integrated Power-Reset circuitry monitoring the powering supply requires a minimum rise rate for the VDDIN_5 power supply.

See Table 7-2 on page 51 for the minimum rise rate value.

If the application can not ensure that the minimum rise rate condition for the VDDIN power supply is met, the following configuration can be used:

- A logic “0” value is applied during power-up on pin RESET_N until:
  - VDDIN_5 rises above 4.5V in 5V single supply mode.
  - VDDIN_33 rises above 3V in 3.3V single supply mode.

Table 7-8. Crystal Oscillator Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{OUT}	Crystal oscillator frequency		0.4		20	MHz
C_i	Internal equivalent load capacitance			1.7		pF
$t_{STARTUP}$	Startup time	f_{OUT} = 8MHz SCIF.OSCCTRL.GAIN = 1(1)		975		us
		f_{OUT} = 16MHz SCIF.OSCCTRL.GAIN = 2(1)		1100		us

Notes: 1. Please refer to the SCIF chapter for details.

7.6.2 32KHz Crystal Oscillator (OSC32K) Characteristics

7.6.2.1 Digital Clock Characteristics

The following table describes the characteristics for the oscillator when a digital clock is applied on XIN32.

Table 7-9. Digital 32KHz Clock Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Units
f_{CPXIN}	XIN32 clock frequency			32.768	5000	KHz
t_{CPXIN}	XIN32 clock period		200			ns
t_{CHXIN}	XIN32 clock high half-priod		0.4 x t_{CPXIN}		0.6 x t_{CPXIN}	ns
t_{CLXIN}	XIN32 clock low half-priod		0.4 x t_{CPXIN}		0.6 x t_{CPXIN}	ns
C_{IN}	XIN32 input capacitance			2		pF

7.6.2.2 Crystal Oscillator Characteristics

Figure 7-2 and the equation above also applies to the 32KHz oscillator connection. The user must choose a crystal oscillator where the crystal load capacitance C_L is within the range given in the table. The exact value of C_L can then be found in the crystal datasheet..

Table 7-10. 32 KHz Crystal Oscillator Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{OUT}	Crystal oscillator frequency			32 768		Hz
$t_{STARTUP}$	Startup time	R_S = 50 kOhm, C_L = 12.5pF		2		s
C_L	Crystal load capacitance		6		15	pF
C_i	Internal equivalent load capacitance			1.4		pF

7.9 Timing Characteristics

7.9.1 Startup, Reset, and Wake-up Timing

The startup, reset, and wake-up timings are calculated using the following formula:

$$t = t_{CONST} + N_{CPU} \times t_{CPU}$$

Where t_{CONST} and N_{CPU} are found in Table 7-44. t_{CONST} is the delay relative to RCSYS, t_{CPU} is the period of the CPU clock. If another clock source than RCSYS is selected as CPU clock the startup time of the oscillator, $t_{OSCSTART}$, must be added to the wake-up time in the stop, deepstop, and static sleep modes. Please refer to the source for the CPU clock in the "Oscillator Characteristics" on page 57 for more details about oscillator startup times.

Table 7-44. Maximum Reset and Wake-up Timing

Parameter		Measuring	Max t_{CONST} (in µs)	Max N_{CPU}
Startup time from power-up, using regulator		VDDIN_5 rising (10 mV/ms) Time from V_{VDDIN_5}=0 to the first instruction entering the decode stage of CPU. VDDCORE is supplied by the internal regulator.	2600	0
Startup time from reset release		Time from releasing a reset source (except POR, BOD18, and BOD33) to the first instruction entering the decode stage of CPU.	1240	0
Wake-up	Idle	From wake-up event to the first instruction entering the decode stage of the CPU.	0	19
	Frozen		268	209
	Standby		268	209
	Stop		268+ $t_{OSCSTART}$	212
	Deepstop		268+ $t_{OSCSTART}$	212
	Static		268+ $t_{OSCSTART}$	212

Maximum SPI Frequency, Master Output

The maximum SPI master output frequency is given by the following formula:

$$f_{SPCKMAX} = MIN(f_{PINMAX}, \frac{1}{SPIn}, \frac{f_{CLKSPI} \times 2}{9})$$

Where $SPIn$ is the MOSI delay, USPI2 or USPI5 depending on CPOL and NCPHA. f_{PINMAX} is the maximum frequency of the SPI pins. Please refer to the I/O Pin Characteristics section for the maximum frequency of the pins. f_{CLKSPI} is the maximum frequency of the CLK_SPI. Refer to the SPI chapter for a description of this clock.

Maximum SPI Frequency, Master Input

The maximum SPI master input frequency is given by the following formula:

$$f_{SPCKMAX} = MIN(\frac{1}{SPIn + t_{VALID}}, \frac{f_{CLKSPI} \times 2}{9})$$

Where $SPIn$ is the MISO setup and hold time, USPI0 + USPI1 or USPI3 + USPI4 depending on CPOL and NCPHA. T_{VALID} is the SPI slave response time. Please refer to the SPI slave datasheet for T_{VALID} . f_{CLKSPI} is the maximum frequency of the CLK_SPI. Refer to the SPI chapter for a description of this clock.

7.9.3.2 Slave mode

Figure 7-8. USART in SPI Slave Mode With (CPOL= 0 and CPHA= 1) or (CPOL= 1 and CPHA= 0)

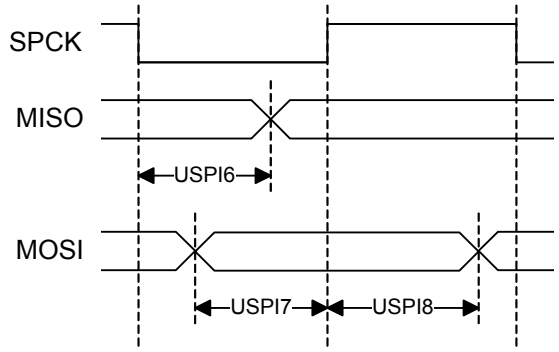


Figure 7-12. SPI Master Mode With (CPOL= 0 and NCPHA= 1) or (CPOL= 1 and NCPHA= 0)

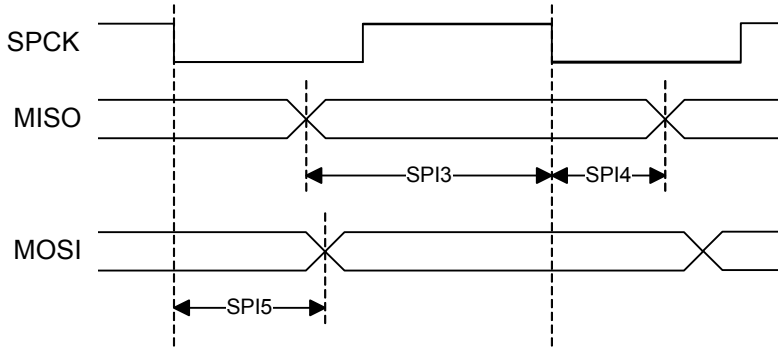


Table 7-48. SPI Timing, Master Mode[1]

Symbol	Parameter	Conditions	Min	Max	Units
SPI0	MISO setup time before SPCK rises	external capacitor = 40pF	28.5+ (t_{CLK_SPI})/2		ns
SPI1	MISO hold time after SPCK rises		0		ns
SPI2	SPCK rising to MOSI delay			10.5	ns
SPI3	MISO setup time before SPCK falls		28.5 + (t_{CLK_SPI})/2		ns
SPI4	MISO hold time after SPCK falls		0		ns
SPI5	SPCK falling to MOSI delay			10.5	ns

Note: 1. These values are based on simulation and characterization of other AVR microcontrollers manufactured in the same process technology. These values are not covered by test limits in production.

Maximum SPI Frequency, Master Output

The maximum SPI master output frequency is given by the following formula:

$$f_{SPCKMAX} = MIN(f_{PINMAX}, \frac{1}{SPIn})$$

Where $SPIn$ is the MOSI delay, SPI2 or SPI5 depending on CPOL and NCPHA. f_{PINMAX} is the maximum frequency of the SPI pins. Please refer to the I/O Pin Characteristics section for the maximum frequency of the pins.

Maximum SPI Frequency, Master Input

The maximum SPI master input frequency is given by the following formula:

$$f_{SPCKMAX} = \frac{1}{SPIn + t_{VALID}}$$

Where $SPIn$ is the MISO setup and hold time, SPI0 + SPI1 or SPI3 + SPI4 depending on CPOL and NCPHA. t_{VALID} is the SPI slave response time. Please refer to the SPI slave datasheet for t_{VALID} .

7.9.7 EBI Timings

See EBI I/O lines description for more details.

Table 7-52. SMC Clock Signal.

Symbol	Parameter	Max[1]	Units
$1/(t_{CPSMC})$	SMC Controller clock frequency	f_{cpu}	MHz

Note: 1. The maximum frequency of the SMC interface is the same as the max frequency for the HSB.

Table 7-53. SMC Read Signals with Hold Settings[1]

Symbol	Parameter	Conditions	Min	Units
NRD Controlled (READ_MODE = 1)				
SMC_1	Data setup before NRD high	V_{VDD} = 3.0V, drive strength of the pads set to the lowest, external capacitor = 40pF	32.5	ns
SMC_2	Data hold after NRD high		0	
SMC_3	NRD high to NBS0/A0 change[2]		nrd hold length * t_{CPSMC} - 1.5	
SMC_4	NRD high to NBS1 change[2]		nrd hold length * t_{CPSMC} - 0	
SMC_5	NRD high to NBS2/A1 change[2]		nrd hold length * t_{CPSMC} - 0	
SMC_7	NRD high to A2 - A25 change[2]		nrd hold length * t_{CPSMC} - 5.6	
SMC_8	NRD high to NCS inactive[2]		(nrd hold length - ncs rd hold length) * t_{CPSMC} - 1.3	
SMC_9	NRD pulse width		nrd pulse length * t_{CPSMC} - 0.6	
NRD Controlled (READ_MODE = 0)				
SMC_{10}	Data setup before NCS high	V_{VDD} = 3.0V, drive strength of the pads set to the lowest, external capacitor = 40pF	34.1	ns
SMC_{11}	Data hold after NCS high		0	
SMC_{12}	NCS high to NBS0/A0 change[2]		ncs rd hold length * t_{CPSMC} - 3	
SMC_{13}	NCS high to NBS0/A0 change[2]		ncs rd hold length * t_{CPSMC} - 2	
SMC_{14}	NCS high to NBS2/A1 change[2]		ncs rd hold length * t_{CPSMC} - 1.1	
SMC_{16}	NCS high to A2 - A25 change[2]		ncs rd hold length * t_{CPSMC} - 7.2	
SMC_{17}	NCS high to NRD inactive[2]		(ncs rd hold length - nrd hold length) * t_{CPSMC} - 2.2	
SMC_{18}	NCS pulse width		ncs rd pulse length * t_{CPSMC} - 3	

Note: 1. These values are based on simulation and characterization of other AVR microcontrollers manufactured in the same process technology. These values are not covered by test limits in production.

2. hold length = total cycle duration - setup duration - pulse duration. “hold length” is for “ncs rd hold length” or “nrd hold length”.

Table 7-58. SDRAM Signal[1]

Symbol	Parameter	Conditions	Min	Units
$SDRAMC_1$	SDCKE high before SDCK rising edge	V_{VDD} = 3.0V, drive strength of the pads set to the highest, external capacitor = 40 pF on SDRAM pins except 8 pF on SDCK pins	5.6	ns
$SDRAMC_2$	SDCKE low after SDCK rising edge		7.3	
$SDRAMC_3$	SDCKE low before SDCK rising edge		6.8	
$SDRAMC_4$	SDCKE high after SDCK rising edge		8.3	
$SDRAMC_5$	SDCS low before SDCK rising edge		6.1	
$SDRAMC_6$	SDCS high after SDCK rising edge		8.4	
$SDRAMC_7$	RAS low before SDCK rising edge		7	
$SDRAMC_8$	RAS high after SDCK rising edge		7.7	
$SDRAMC_9$	SDA10 change before SDCK rising edge		6.4	
$SDRAMC_{10}$	SDA10 change after SDCK rising edge		7.1	
$SDRAMC_{11}$	Address change before SDCK rising edge		4.7	
$SDRAMC_{12}$	Address change after SDCK rising edge		4.4	
$SDRAMC_{13}$	Bank change before SDCK rising edge		6.2	
$SDRAMC_{14}$	Bank change after SDCK rising edge		6.9	
$SDRAMC_{15}$	CAS low before SDCK rising edge		6.6	
$SDRAMC_{16}$	CAS high after SDCK rising edge		7.8	
$SDRAMC_{17}$	DQM change before SDCK rising edge		6	
$SDRAMC_{18}$	DQM change after SDCK rising edge		6.7	
$SDRAMC_{19}$	D0-D15 in setup before SDCK rising edge		6.4	
$SDRAMC_{20}$	D0-D15 in hold after SDCK rising edge		0	
$SDRAMC_{23}$	SDWE low before SDCK rising edge		7	
$SDRAMC_{24}$	SDWE high after SDCK rising edge		7.4	
$SDRAMC_{25}$	D0-D15 Out valid before SDCK rising edge		5.2	
$SDRAMC_{26}$	D0-D15 Out valid after SDCK rising edge		5.6	

Note: 1. These values are based on simulation and characterization of other AVR microcontrollers manufactured in the same process technology. These values are not covered by test limits in production.

8. Mechanical Characteristics

8.1 Thermal Considerations

8.1.1 Thermal Data

Table 8-1 summarizes the thermal resistance data depending on the package.

Table 8-1. Thermal Resistance Data

Symbol	Parameter	Condition	Package	Typ	Unit
θ_{JA}	Junction-to-ambient thermal resistance	No air flow	QFN64	20.0	°C/W
θ_{JC}	Junction-to-case thermal resistance		QFN64	0.8	
θ_{JA}	Junction-to-ambient thermal resistance	No air flow	TQFP64	40.5	°C/W
θ_{JC}	Junction-to-case thermal resistance		TQFP64	8.7	
θ_{JA}	Junction-to-ambient thermal resistance	No air flow	TQFP100	39.3	°C/W
θ_{JC}	Junction-to-case thermal resistance		TQFP100	8.5	
θ_{JA}	Junction-to-ambient thermal resistance	No air flow	LQFP144	38.1	°C/W
θ_{JC}	Junction-to-case thermal resistance		LQFP144	8.4	

8.1.2 Junction Temperature

The average chip-junction temperature, T_J, in °C can be obtained from the following:

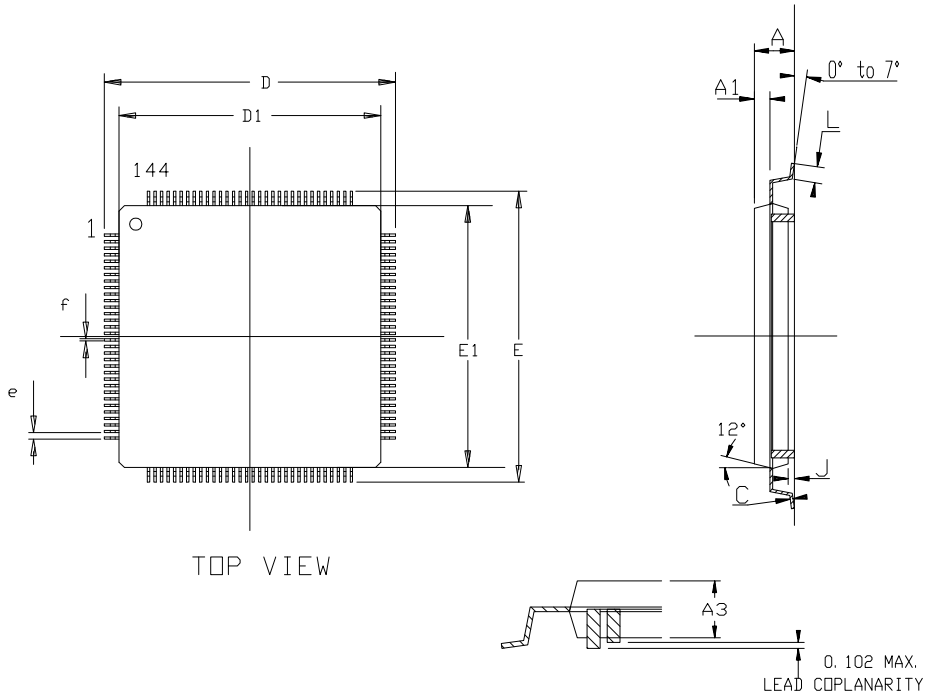
1. $T_J = T_A + (P_D \times \theta_{JA})$
2. $T_J = T_A + (P_D \times (\theta_{HEATSINK} + \theta_{JC}))$

where:

- θ_{JA} = package thermal resistance, Junction-to-ambient (°C/W), provided in Table 8-1 on page 90.
- θ_{JC} = package thermal resistance, Junction-to-case thermal resistance (°C/W), provided in Table 8-1 on page 90.
- $\theta_{HEAT\ SINK}$ = cooling device thermal resistance (°C/W), provided in the device datasheet.
- P_D = device power consumption (W) estimated from data provided in the section "Power Consumption" on page 51.
- T_A = ambient temperature (°C).

From the first equation, the user can derive the estimated lifetime of the chip and decide if a cooling device is necessary or not. If a cooling device is to be fitted on the chip, the second equation should be used to compute the resulting average chip-junction temperature T_J in °C.

Figure 8-4. LQFP-144 package drawing



	MM			INCH		
	Min	Nom	Max	Min	Nom	Max
A	–	–	1.60	–	–	.063
C	0.09	–	0.20	.004	–	.008
A3	1.35	1.40	1.45	.053	.055	.057
D	21.90	22.00	22.10	.862	.866	.870
D1	19.90	20.00	20.10	.783	.787	.791
E	21.90	22.00	22.10	.862	.866	.870
E1	19.90	20.00	20.10	.783	.787	.791
J	0.05	–	0.15	.002	–	.006
L	0.45	0.60	0.75	.018	.024	.030
e	0.50 BSC			.0197 BSC		
f	0.22 BSC			.009 BSC		

Table 8-11. Device and Package Maximum Weight

1300	mg

Table 8-12. Package Characteristics

Moisture Sensitivity Level	Jdec J-STD0-20D - MSL 3

Table 8-13. Package Reference

JEDEC Drawing Reference	MS-026
JESD97 Classification	E3

8.3 Soldering Profile

Table 8-14 gives the recommended soldering profile from J-STD-20.

Table 8-14. Soldering Profile

Profile Feature	Green Package
Average Ramp-up Rate (217°C to Peak)	3°C/sec
Preheat Temperature 175°C ±25°C	Min. 150 °C, Max. 200 °C
Temperature Maintained Above 217°C	60-150 sec
Time within 5·C of Actual Peak Temperature	30 sec
Peak Temperature Range	260 °C
Ramp-down Rate	6 °C/sec
Time 25·C to Peak Temperature	Max. 8 minutes

Note: It is recommended to apply a soldering temperature higher than 250°C.

A maximum of three reflow passes is allowed per component.

2 **Requesting clocks in idle sleep modes will mask all other PB clocks than the requested**
In idle or frozen sleep mode, all the PB clocks will be frozen if the TWIS or the AST need to wake the cpu up.
Fix/Workaround
Disable the TWIS or the AST before entering idle or frozen sleep mode.

3 **TWIS may not wake the device from sleep mode**
If the CPU is put to a sleep mode (except Idle and Frozen) directly after a TWI Start condition, the CPU may not wake upon a TWIS address match. The request is NACKed.
Fix/Workaround
When using the TWI address match to wake the device from sleep, do not switch to sleep modes deeper than Frozen. Another solution is to enable asynchronous EIC wake on the TWIS clock (TWCK) or TWIS data (TWD) pins, in order to wake the system up on bus events.

10.2.6 SCIF

1 **PLLCOUNT value larger than zero can cause PLLEN glitch**
Initializing the PLLCOUNT with a value greater than zero creates a glitch on the PLLEN signal during asynchronous wake up.
Fix/Workaround
The lock-masking mechanism for the PLL should not be used.
The PLLCOUNT field of the PLL Control Register should always be written to zero.

2 **PLL lock might not clear after disable**
Under certain circumstances, the lock signal from the Phase Locked Loop (PLL) oscillator may not go back to zero after the PLL oscillator has been disabled. This can cause the propagation of clock signals with the wrong frequency to parts of the system that use the PLL clock.
Fix/Workaround
PLL must be turned off before entering STOP, DEEPSTOP or STATIC sleep modes. If PLL has been turned off, a delay of 30us must be observed after the PLL has been enabled again before the SCIF.PLL0LOCK bit can be used as a valid indication that the PLL is locked.

3 **BOD33 reset locks the device**
If BOD33 is enabled as a reset source (SCIF.BOD33.CTRL=0x1) and when VDDIN_33 power supply voltage falls below the BOD33 voltage (SCIF.BOD33.LEVEL), the device is locked permanently under reset even if the power supply goes back above BOD33 reset level. In order to unlock the device, an external reset event should be applied on RESET_N.
Fix/Workaround
Use an external BOD on VDDIN_33 or an external reset source.

10.2.7 SPI

1 **SPI data transfer hangs with CSR0.CSAAT==1 and MR.MODFDIS==0**
When CSR0.CSAAT==1 and mode fault detection is enabled (MR.MODFDIS==0), the SPI module will not start a data transfer.
Fix/Workaround
Disable mode fault detection by writing a one to MR.MODFDIS.

11. Datasheet Revision History

Please note that the referring page numbers in this section are referred to this document. The referring revision in this section are referring to the document revision.

11.1 Rev. D – 01/12

1	Errata: Updated
2	PM: Clock Mask Table Updated
3	Fixed PLLOPT field description in SCIF chapter
4	MDMA: Swapped bit descriptions for IER and IDR
5	MACB: USRIO register description and bit descriptions for IMR/IDR/IER Updated
6	USBC: UPCON.PFREEZE and UPINRQn description Updated
7	ACIFA: Updated
8	ADCIFA: CFG.MUXSET, SSMQ description and conversion results section Updated
9	DACIFB: Calibration section Updated
10	Electrical Characteristics: ADCREFP/ADCREFN added

11.2 Rev. C – 08/11

1	Electrical Characteristics Updated: - I/O Pins characteristics - 8MHz/1MHz RC Oscillator (RC8M) characteristics - 1.8V Voltage Regulator characteristics - 3.3V Voltage Regulator characteristics - 1.8VBrown Out Detector (BOD18) characteristics - 3.3VBrown Out Detector (BOD33) characteristics - 5VBrown Out Detector (BOD50) characteristics - Analog to Digital Converter (ADC) and sample and hold (S/DH) Characteristics - Analog Comparator characteristics
2	Errata: Updated
3	TWIS: Updated

11.3 Rev. B – 03/11

1	Package and pinout: Added supply column. Updated peripheral functions
2	Supply and Startup Considerations: Updated I/O lines power
3	PM: Added AWEN description
4	SCIF: Added VREGCR register

5	AST: Updated digital tuner formula
6	SDRAMC: cleaned-up SDCS/NCS names. Added VERSION register
7	SAU: Updated SR.IDLE
8	USART: Updated
9	CANIF: Updated address map figure
10	USBC: Updated
11	DACIFB: Updated
12	Programming and Debugging: Added JTAG Data Registers section
13	Electrical Characteristics: Updated
14	Ordering Information: Updated
15	Errata: Updated

11.4 Rev. A – 10/10

1	Initial revision